

## **METHOD AND APPARATUS FOR DETECTING A PLASMA**

### **ABSTRACT OF DISCLOSURE**

The present invention presents an improved apparatus and method for monitoring a material processing system, where the material processing system includes a processing tool, test signal source, and a filter/detector. The test signal source providing a first test signal and a second test signal to the processing chamber, and the filter/detector detecting an intermodulation product of the first test signal and the second test signal generated when a plasma is created.